

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 268669US26PCT		SERIAL NO. 10/529,184	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takahiro HORIGUCHI, et al.			
				FILING DATE March 24, 2005		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>mm</i>	AA	6 143 081	11/07/00	SHINRIKI et al.			
<i>mm</i>	AB	5 903 711	05/11/99	OKASE			
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>mm</i>	AO	060138/1994	08/19/94	JP			NO
<i>mm</i>	AP	05-047687	02/26/93	JP (with English abstract)			NO
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>sh</i>	AW	LU, Z.H. et al. "SiO2 film thickness metrology by x-ray photoelectron spectroscopy", Appl. Phys. Lett., vol. 71, no. 19, pages 2764-2766 1997					
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>sh</i>					Date Considered 5/12/07		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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FILING DATE March 24, 2005				GROUP 2812			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
/SM/	AO	WO 02/23614 A1	3/21/2002	WIPO (with English Abstract)		X	
/SM/	AP	10-501099	1/27/1998	Japan (with English Abstract of corresponding WO 95/31582)		X	
/SM/	AQ	6-267864	9/22/1994	Japan (with English Abstract)		X	
/SM/	AR	3-77315	4/2/1991	Japan (with English Abstract)		X	
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				/Sylvia Macarthur/		Date Considered 05/12/2007	
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